Please type a plus sign (+) inside this box → [+]

Substitute for form 1449B/PTO	Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT *(use as many sheets as necessary)*	Application Number	09/850,195
	Filing Date	May 8, 2001
	First Named Inventor	THEKKATH
	Group Art Unit	2113
	Examiner Name	Baderman, Scott T.

Sheet	1	of	2	Attorney Docket Number	MTEC-008/00US

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
JC	D1	F. Chow et al., "Engineering a RISC Compiler System," *IEEE COMP-CON*, March 1986, pp. 132-137.	
JC	D2	FALOUTSOS, CHRISTOS et al., "Description and Performance Analysis of Signature File Methods for Office Filing", ACM Transactions on Office Information Systems, (July 1987), 5:3:237-257.	
JC	D3	Susan J. EGGERS, et al., "Techniques for Efficient Inline Tracing on a Shared-Memory Multiprocessor," University of Washington, *1990 ACM*, pp. 37-47.	
JC	D4	M.D. Smith, "Tracing with Pixie," *Technical Report CSL-TR-91-497*, Stanford University, Computer Systems Laboratory, November 1991, pp. 1-29.	
JC	D5	ATOM Reference Manual, *Digital Equipment Corporation*, Massachusetts, December 1993, pp. 1-32.	
JC	D6	A. Srivastaba et al., "ATOM: A System for Building Customized Program Analysis Tools," *WRL, Research Report 94/2*, Digital Equipment Corporation, Massachusetts, March 1994, pp. 1-23.	
JC	D7	ATOM User Manual, Digital Equipment Corporation, March 1994, pp. 1-28.	
JC	D8	B. Cmelik et al., "Shade: A Fast Instruction-Set Simulator for Execution Profiling," *Proceedings of the 1994 ACM SIGMETRICS Conference*, SIGMETRICS, California, May 1994, pp. 128-137.	
JC	D9	Richard A. UHLIG, et al., "Trace-Driven Memory Simulation: A Survey," Intel Microcomputer Research Lab; University of Michigan, *ACM Computing Surveys*, Vol. 29, No. 2, June 1997, pp. 128-170.	
JC	D10	Eric ROTENBERG, et al., "Trace Processors," University of Wisconsin, 1997 *IEEE Service Center*, 12 pp.	
JC	D11	E.N. ELNOZAHY, "Address Trace Compression Through Loop Detection and Reduction," ©*1999 ACM 1-58113-083*, pp. 214, 215.	
JC	D12	MIPS Technologies; "MIPS64™ 5K™ Processor Core Family Integrator's Guide;" [Document No. MD00106]; ©*1999-2001 MIPS Technologies, Inc.*; Rev. 02.00; January 15, 2001; pp. I-VIII, 1-75.	
JC	D13	Darren JONES, "Opal Coprocessor Interface," *MIP Proprietary/Confidential*, June 4, 1999, pp. 1-18.	
JC	D14	Darren JONES, *MIPSS64™ 5KC™ Processor Cores User's Manual*, Rev. 1.0, July 4, 1999, pp. 6-1 to 6-26.	

714808 v1/PA

rc	D15	*MIPSS64™ SKC™ Processor Cores User's Manual*, Rev. 1.0.1., 1999, pp. 247-276.	
rc	D16	Embedded Trace Macrocell, (Rev. 1) Specification, (2000).	
rc	D17	MIPS Technologies; "MIPS64™ 5K™ Processor Core Integrator's Guide;" [Document No. MD00056]; *MIPS Technologies, Inc.*; Rev. 1.2; August 11, 2000; pp. 1-11, 1-82.	
rc	D18	MIPS Technologies; "Core Processor Interface Specification;" [Document No. MD00068]; *MIPS Technologies, Inc.*; Rev. 1.11; March 30, 2001; pp. 1-26.	

Examiner Signature	*rccuun*	Date Considered	1/5/06

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

[1] Unique citation designation number.
[2] Applicant is to place a check mark here if English language Translation attached.

Substitute for form 1449A/PTO	Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT *(use as many sheets as necessary)*	Application Number	09/850,195
	Filing Date	May 8, 2001
	First Named Inventor	THEKKATH
	Group Art Unit	2113
	Examiner Name	Baderman, Scott T.
Sheet **1** of **3**	Attorney Docket Number	MTEC-008/00US

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	U.S. Patent Document Number	Kind Code[2] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
ᗭᘓᑕ	P1	5,084,814		Vaglica et al.	01/28/1992
	P2	6,032,268		Swoboda et al.	09/29/2000
	P3	6,687,865		Dervisoglu et al.	02/23/2004
	P4	6,754,804		Hudepohl et al.	06/22/2004
	P5	09/751,747		Hudepohl et al.	12/29/2000
	P6	09/751,748		Hudepohl et al.	12/29/2000
	P7	09/844,671		Thekkath et al.	04/30/2001
	P8	~~09/944,669~~ 09 844 669		Thekkath	04/30/2001
	P9	09/894,832		Thekkath et al.	06/29/2001
	P10	09/844,668		Thekkath et al.	04/30/2001
	P11	09/844,672		Thekkath	04/30/2001
	P12	09/844,673		Thekkath	04/30/2001
	P13	09/844,271		Thekkath	04/30/2001
	P14	09/894,831		Treue et al.	06/29/2001
	P15	09/894,830		Treue et al.	06/29/2001
ᗭᘓᑕ	P16	09/844,670		Thekkath	04/30/2001

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document Office[3]	Number[4]	Kind Code[5] (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T[6]

Examiner Signature	*(signature)*	Date Considered	1/5/06

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

[1] Unique citation designation number.
[2] See attached Kinds of U.S. Patent Documents.
[3] Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).
[4] For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.
[5] Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible.
[6] Applicant is to place a check mark here if English language Translation is attached.